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(54) ABNORMALITY DIAGNOSIS DEVICE AND ABNORMALITY DIAGNOSIS METHOD

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(57) **ABSTRACT**

An abnormality diagnosis device includes: a first interface to obtain a value of a driving current for driving a motor; and a processor to access a database including calculation data to be used to calculate a degree of abnormality of the motor, wherein the processor extracts a feature quantity for calculating the degree of abnormality from a current waveform specified by a value of the driving current, and calculates the degree of abnormality of the motor based on the extracted feature quantity and the calculation data.